

Diode

Emitter Controlled 4 Medium Power Technology IDC21D120T8M

Data Sheet

Industrial Power Control



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Diode Chip in Emitter Controlled 4 Medium Power Technology

Features:

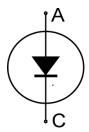
- 1200V Emitter Controlled 4 technology
 110µm chip
- Soft, fast switching
- Low reverse recovery charge
- Small temperature coefficient

Recommended for:

Low / medium power modules

Applications:

• Low / medium power drives



Chip Type	V _R	I _{Fn}	Die Size	Package
IDC21D120T8M	1200V	35A	6.25mm x 3.40mm	Sawn on foil

Mechanical Parameters

Die size		6.25 x 3.40			
Area total		21.25			
Anode pad size		5.276 x 2.446			
Silicon thickness		110	μm		
Wafer size		200	mm		
Maximum possible chi	ps per wafer	1279			
Passivation frontside		Photoimide			
Pad metal 3200nm AlSiCu					
Backside metal		Ni Ag – system To achieve a reliable solder connection it is stro recommended not to consume the Ni layer complete production process			
Die bond	bond Electrically conductive epoxy glue and soft solder				
Wire bond	Vire bond AI, ≤500μm				
Reject ink dot size		∅ 0.65mm; max 1.2mm			
Storage environment	for original and sealed MBB bags	Ambient atmosphere air, temperature 17°C – 25°C			
(<6 months)	for open MBB bags	Acc. IEC 62258-3; Section 9.4 Storage Environment.			

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Maximum Ratings

In general, from reliability and lifetime point of view, the lower the operation junction temperature and/or the applied voltage, the greater the expected lifetime of any semiconductor device.

Parameter	Symbol	Conditions	Value	Unit
Repetitive peak reverse voltage	V_{RRM}	T _{vj} =25°C	1200	V
Continuous forward current ¹	I _F		-	_
Maximum repetitive forward current ²	I _{FRM}		70	A
Junction temperature	$T_{\rm vj}$		-40+175	°C
Operating junction temperature	T _{vj op}		-40+150	°C

Static Characteristics (tested on wafer), T_{vi}=25°C

Parameter	Symbol	Conditions	Value			Unit
	Syllibol	Conditions	min.	typ.	max.	Offic
Reverse leakage current	I _R	V _R =1200V	-	-	7.7	μA
Cathode-anode breakdown voltage	V_{BR}	I _R =0.25mA	1200	-	-	V
Forward voltage drop	V_{F}	<i>I</i> _F =35A	1.35	1.70	2.05	

Further Electrical Characteristics

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

Application example	FP35R12KT4_B11	Rev. 3.0

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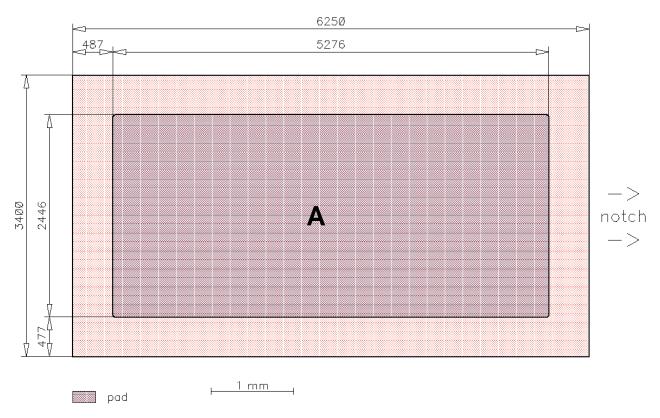
¹ Depending on thermal properties of assembly.

² Not subject to production test - verified by design/characterization.



Chip Drawing





A = Anode pad



Bare Die Product Specific	Bare	Die	Product	Specifics
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Description

Test coverage at wafer level cannot cover all application conditions. Therefore it is recommended to test all characteristics which are relevant for the application at package level, including RBSOA and SCSOA.

AQL 0.65 for	visual inspection according to failure catalogue	
Electrostatic I	Discharge Sensitive Device according to MIL-STD 883	
Revision His	tory	
Revision	Subjects (major changes since last revision)	Date
2.0	Final data sheet	22.08.2016
Relevant Ap	plication Notes	

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